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02/26/02

MT

PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10082288	02/26/2002	250	49.1	2876	Asy. [Signature]

**APPLICANTS: Sato Mitsugu; Otake Tadashi; Ezumi Makoto; Takane Atsushi; Yoshida Shoji; Yamaguchi Satoru; Ozawa Yasuhiko;

**CONTINUING DATA VERIFIED:

[Signature]

** FOREIGN APPLICATIONS VERIFIED:

[Signature]

JAPAN 2001-161588 05/30/2001
JAPAN 2001-208674 07/10/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed: <input checked="" type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met: <input checked="" type="checkbox"/> yes <input type="checkbox"/> no		H6808.0005/P005
Verified and Acknowledged Examiners's initials		

TITLE : Charged particle beam alignment method and charged particle beam apparatus

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L/Rev. 1-94

Best Available Copy

DRAWINGS			CLAIMS ALLOWED	
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
(Assistant Examiner) _____ (Date) _____ (Primary Examiner) _____ (Date) _____ (Legal Instruments Examiner) _____ (Date) _____			NOTICE OF ALLOWANCE MAILED	
			ISSUE FEE	
			Amount Due	Date Paid
			ISSUE BATCH NUMBER	

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